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Wide Temperature Range Version 4 M SRAM (512-kword × 8-bit)



ADE-203-1211C (Z) Rev. 3.0 Dec. 18, 2002

Description

The Hitachi HM628512CI is a 4-Mbit static RAM organized 512-kword \times 8-bit. HM628512CI Series has realized higher density, higher performance and low power consumption by employing CMOS process technology (6-transistor memory cell). The HM628512CI Series offers low power standby power dissipation; therefore, it is suitable for battery backup systems. It has packaged in 32-pin SOP, 32-pin TSOP II and 32-pin DIP.

Features

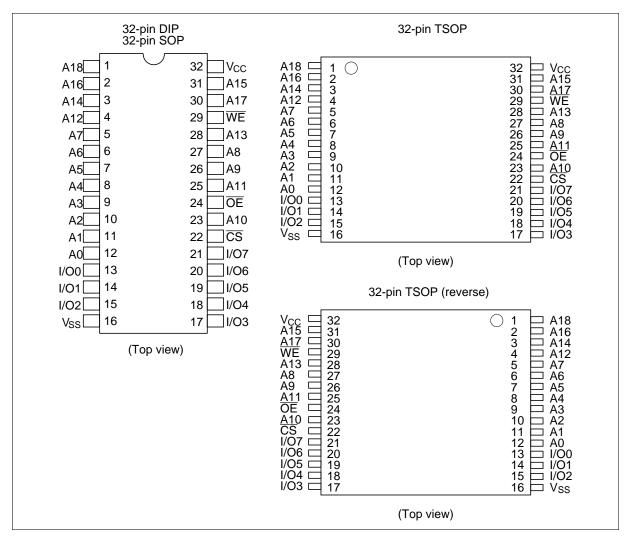
- Single 5 V supply
- Access time: 55/70 ns (max)
- Power dissipation
 - Active: 10 mW/MHz (typ)
 - Standby: $4 \mu W (typ)$
- Completely static memory. No clock or timing strobe required
- Equal access and cycle times
- Common data input and output: Three state output
- Directly TTL compatible: All inputs and outputs
- Battery backup operation
- Operating temperature: -40 to +85°C

Ordering Information

Туре No.	Access time	Package
HM628512CLPI-7	70 ns	600-mil 32-pin plastic DIP (DP-32)
HM628512CLFPI-5 HM628512CLFPI-7	55 ns 70 ns	525-mil 32-pin plastic SOP (FP-32D)
HM628512CLTTI-5 HM628512CLTTI-7	55 ns 70 ns	400-mil 32-pin plastic TSOP II (TTP-32D)
HM628512CLRRI-7	70 ns	400-mil 32-pin plastic TSOP II reverse (TTP-32DR)



Pin Arrangement

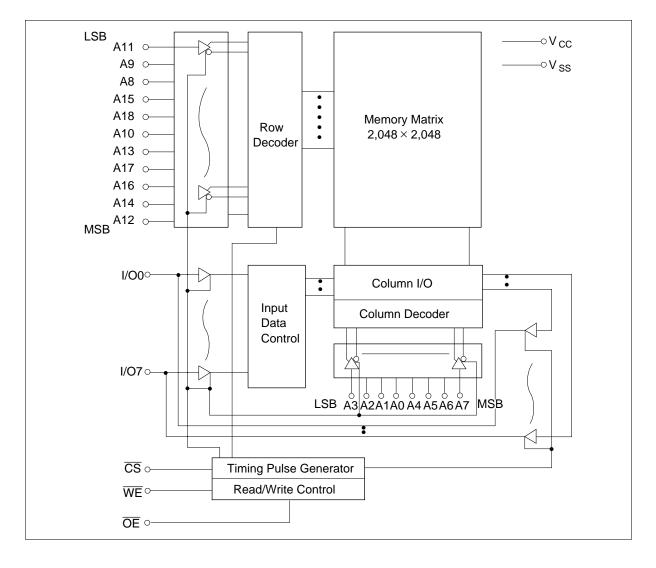


Pin Description

Pin name	Function
A0 to A18	Address input
I/O0 to I/O7	Data input/output
CS	Chip select
ŌĒ	Output enable
WE	Write enable
V _{cc}	Power supply
V _{ss}	Ground



Block Diagram



Function Table

WE	CS	ŌE	Mode	V _{cc} current	Dout pin	Ref. cycle
×	Н	×	Not selected	I_{SB},I_{SB1}	High-Z	_
Н	L	Н	Output disable	I _{cc}	High-Z	_
Н	L	L	Read	I _{cc}	Dout	Read cycle
L	L	Н	Write	I _{cc}	Din	Write cycle (1)
L	L	L	Write	I _{cc}	Din	Write cycle (2)

Note: X: H or L

Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Power supply voltage	V _{cc}	–0.5 to +7.0	V
Voltage on any pin relative to $\rm V_{ss}$	V _T	-0.5^{*1} to V _{cc} + 0.3 ^{*2}	V
Power dissipation	P _T	1.0	W
Operating temperature	Topr	-40 to +85	°C
Storage temperature	Tstg	–55 to +125	°C
Storage temperature under bias	Tbias	-40 to +85	°C

Notes: 1. V_{τ} min: -3.0 V for pulse half-width \leq 30 ns.

2. Maximum voltage is 7.0 V.

Recommended DC Operating Conditions (Ta = -40 to $+85^{\circ}$ C)

Parameter	Symbol	Min	Тур	Max	Unit
Supply voltage	V _{cc}	4.5	5.0	5.5	V
	V _{ss}	0	0	0	V
Input high voltage	V _{IH}	2.4	—	V _{cc} + 0.3	V
Input low voltage	V _{IL}	-0.3*1	_	0.6	V

Note: 1. V_{IL} min: -3.0 V for pulse half-width \leq 30 ns.

DC Characteristics

Parameter		Symbol	Min	Typ*1	Max	Unit	Test conditions
Input leakage current		I _{LI}	_		1	μΑ	$Vin = V_{ss} to V_{cc}$
Output leakage curre	nt	I _{lo}	_	—	1	μΑ	$\overline{\frac{CS}{WE}} = V_{IH} \text{ or } \overline{OE} = V_{IH} \text{ or } $ $\overline{WE} = V_{IL}, V_{I/O} = V_{SS} \text{ to } V_{CC}$
Operating power supply current: DC		I _{cc}		1.5	3	mA	$\overline{CS} = V_{IL},$ others = V_{IH}/V_{IL} , $I_{I/O} = 0$ mA
Operating power supply current	HM628512CI-5	I _{CC1}	—	8	25	mA	$\label{eq:main_state} \begin{split} & \underset{CS}{\text{Min cycle, duty}} = 100\% \\ & \underset{CS}{CS} = V_{\text{IL}}, \text{ others } = V_{\text{IH}} / V_{\text{IL}} \\ & I_{\text{I/O}} = 0 \text{ mA} \end{split}$
	HM628512CI-7	I _{CC1}	—	7	25	mA	
Operating power supply current		I _{CC2}	—	2	5	mA	$\begin{array}{l} \mbox{Cycle time = 1 μs,} \\ \mbox{duty = 100\%} \\ \mbox{I}_{_{I\!O}} = 0 \mbox{ mA, } \overline{\mbox{CS}} \leq 0.2 \mbox{ V} \\ \mbox{V}_{_{I\!H}} \geq V_{_{C\!C}} - 0.2 \mbox{ V}, \mbox{V}_{_{I\!L}} \leq 0.2 \mbox{ V} \end{array}$
Standby power supply current: DC		I _{SB}	—	0.1	0.5	mA	$\overline{\text{CS}} = \text{V}_{\text{IH}}$
Standby power supply current (1): DC		I _{SB1}	—	0.8*2	20* ²	μA	$Vin \ge 0 \text{ V}, \overline{CS} \ge V_{\text{CC}} - 0.2 \text{ V}$
Output low voltage		V _{OL}			0.4	V	I _{oL} = 2.1 mA
Output high voltage		V _{OH}	2.4	_	_	V	Ι _{OH} = -1.0 mA

Notes: 1. Typical values are at V_{cc} = 5.0 V, Ta = +25°C and specified loading, and not guaranteed.

Capacitance (Ta = $+25^{\circ}$ C, f = 1 MHz)

Parameter	Symbol	Тур	Max	Unit	Test conditions
Input capacitance*1	Cin	_	8	pF	Vin = 0 V
Input/output capacitance*1	C _{I/O}	_	10* ²	pF	$V_{I/O} = 0 V$

Note: 1. This parameter is sampled and not 100% tested.

2. $C_{I/O}$ max = 12 pF only for HM628512CLPI Series.

AC Characteristics (Ta = -40 to $+85^{\circ}$ C, V_{CC} = 5 V ± 10%, unless otherwise noted.)

Test Conditions

- Input pulse levels: 0.4 V to 2.4 V
- Input rise and fall time: 5 ns
- Input and output timing reference levels: 1.5 V
- Output load: 1 TTL Gate + C_L (50 pF) (HM628512CI-5)
 - 1 TTL Gate + C_L (100 pF) (HM628512CI-7)

(Including scope and jig)

Read Cycle

		HM628	8512CI				
		-5		-7			
Parameter	Symbol	Min	Мах	Min	Мах	Unit	Notes
Read cycle time	t _{RC}	55	_	70	_	ns	
Address access time	t _{AA}	—	55	—	70	ns	
Chip select access time	t _{co}	—	55	—	70	ns	
Output enable to output valid	t _{oe}	—	25	—	35	ns	
Chip selection to output in low-Z	t _{LZ}	10		10		ns	2
Output enable to output in low-Z	t _{oLZ}	5		5		ns	2
Chip deselection to output in high-Z	t _{HZ}	0	20	0	25	ns	1, 2
Output disable to output in high-Z	t _{oHz}	0	20	0	25	ns	1, 2
Output hold from address change	t _{oh}	10	—	10	—	ns	

Write Cycle

		HM62	8512CI				
		-5		-7		_	
Parameter	Symbol	Min	Max	Min	Max	Unit	Notes
Write cycle time	t _{wc}	55		70	—	ns	
Chip selection to end of write	t _{cw}	50		60	—	ns	4
Address setup time	t _{AS}	0		0		ns	5
Address valid to end of write	t _{AW}	50		60	—	ns	
Write pulse width	t _{wP}	40		50	—	ns	3, 12
Write recovery time	t _{wR}	0		0	—	ns	6
WE to output in high-Z	t _{wHZ}	0	20	0	25	ns	1, 2, 7
Data to write time overlap	t _{DW}	25		30	—	ns	
Data hold from write time	t _{DH}	0		0	—	ns	
Output active from output in high-Z	t _{ow}	5		5	—	ns	2
Output disable to output in high-Z	t _{oHz}	0	20	0	25	ns	1, 2, 7

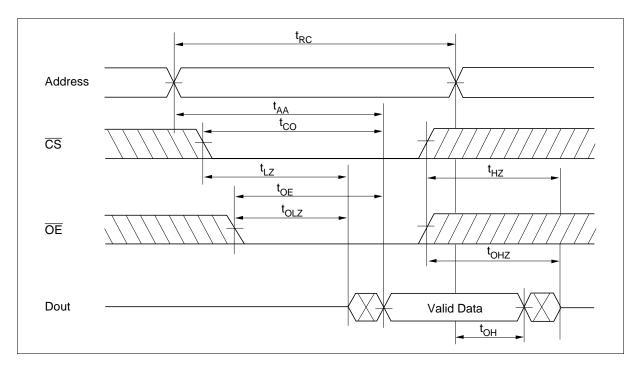
Notes: 1. t_{HZ}, t_{OHZ} and t_{WHZ} are defined as the time at which the outputs achieve the open circuit conditions and are not referred to output voltage levels.

- 2. This parameter is sampled and not 100% tested.
- 3. A write occurs during the overlap (t_{WP}) of a low CS and a low WE. A write begins at the later transition of CS going low or WE going low. A write ends at the earlier transition of CS going high or WE going high. t_{WP} is measured from the beginning of write to the end of write.
- 4. t_{cw} is measured from \overline{CS} going low to the end of write.
- 5. t_{AS} is measured from the address valid to the beginning of write.
- 6. t_{WR} is measured from the earlier of \overline{WE} or \overline{CS} going high to the end of write cycle.
- 7. During this period, I/O pins are in the output state so that the input signals of the opposite phase to the outputs must not be applied.
- 8. If the CS low transition occurs simultaneously with the WE low transition or after the WE transition, the output remain in a high impedance state.
- 9. Dout is the same phase of the write data of this write cycle.
- 10. Dout is the read data of next address.
- 11. If \overline{CS} is low during this period, I/O pins are in the output state. Therefore, the input signals of the opposite phase to the outputs must not be applied to them.
- 12. In the write cycle with \overline{OE} low fixed, t_{WP} must satisfy the following equation to avoid a problem of data bus contention. $t_{WP} \ge t_{DW}$ min + t_{WHZ} max



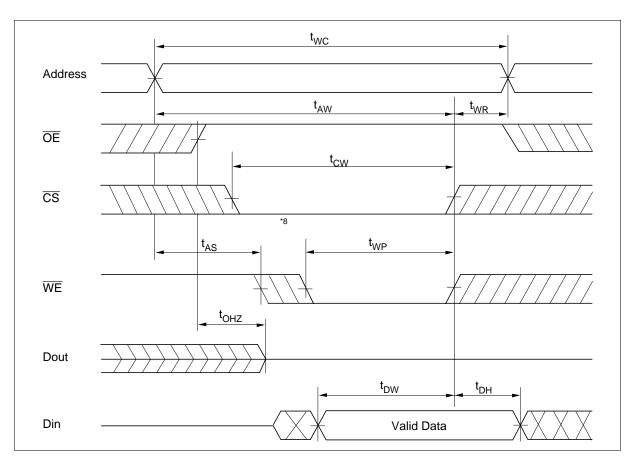
Timing Waveforms

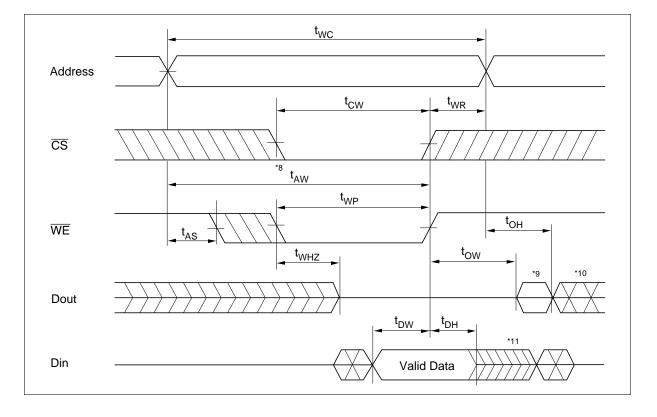
Read Timing Waveform $(\overline{WE}=V_{\rm IH})$





Write Timing Waveform (1) $(\overline{OE} Clock)$





Write Timing Waveform (2) (OE Low Fixed)

Low V_{cc} Data Retention Characteristics (Ta = -40 to +85°C)

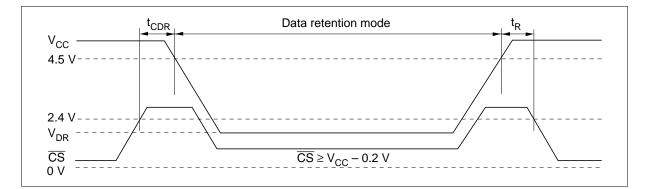
Parameter	Symbol	Min	Тур	Мах	Unit	Test conditions* ²
V_{cc} for data retention	V_{DR}	2	_	_	V	$\overline{\text{CS}} \ge \text{V}_{\text{CC}} - 0.2 \text{ V}, \text{ Vin} \ge 0 \text{ V}$
Data retention current	I _{CCDR}	—	0.8*3	20*1	μΑ	$\frac{V_{cc}}{CS} = 3.0 \text{ V}, \text{ Vin} \ge 0 \text{ V}$ $\overline{CS} \ge V_{cc} - 0.2 \text{ V}$
Chip deselect to data retention time	t_{CDR}	0	—	—	ns	See retention waveform
Operation recovery time	t _R	t_{RC}^{*4}	_	—	ns	

Notes: 1. 10 μ A (max) at Ta = -40 to +40°C.

2. CS controls address buffer, WE buffer, OE buffer, and Din buffer. In data retention mode, Vin levels (address, WE, OE, I/O) can be in the high impedance state.

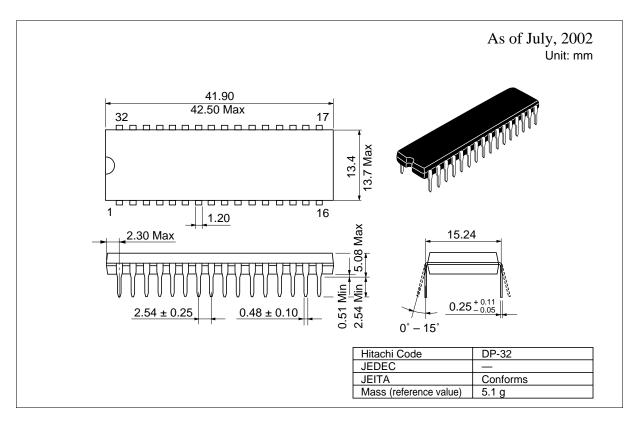
- 3. Typical values are at V_{cc} = 3.0 V, Ta = +25°C and specified loading, and not guaranteed.
- 4. t_{RC} = read cycle time.

Low V_{CC} Data Retention Timing Waveform (\overline{CS} Controlled)



Package Dimensions

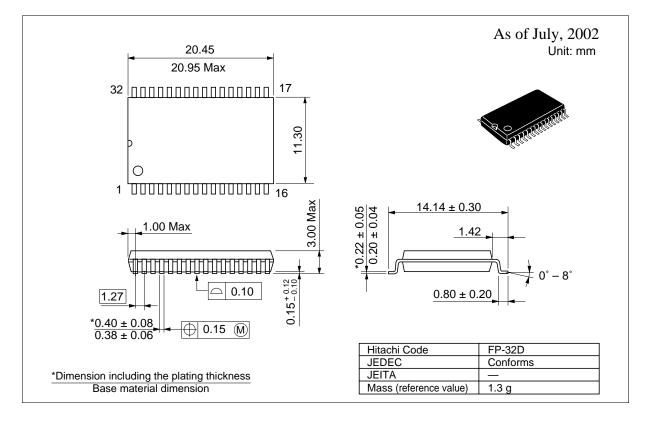
HM628512CLPI Series (DP-32)





Package Dimensions (cont.)

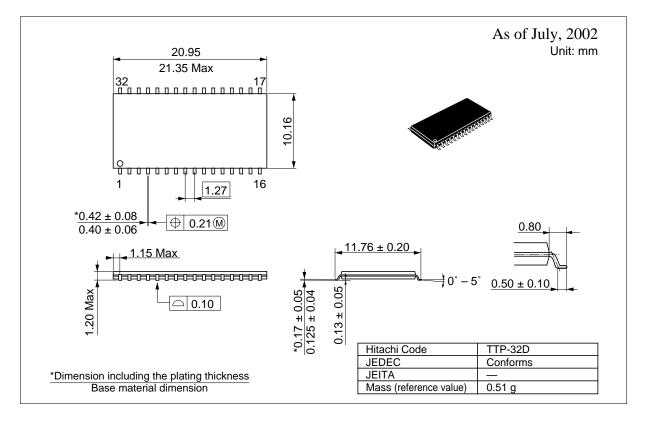
HM628512CLFPI Series (FP-32D)





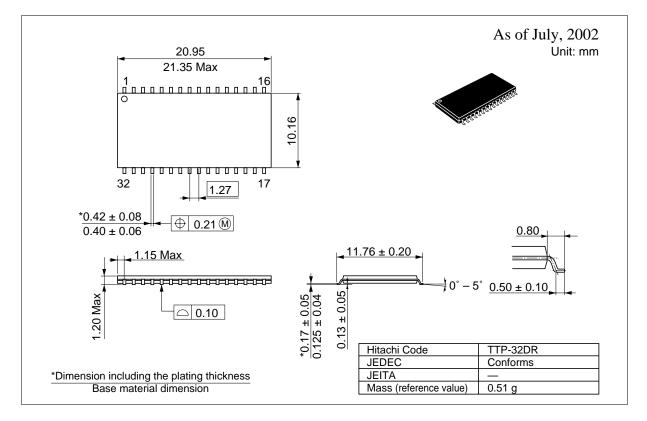
Package Dimensions (cont.)

HM628512CLTTI Series (TTP-32D)



Package Dimensions (cont.)

HM628512CLRRI Series (TTP-32DR)





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Hitachi, Ltd.

Semiconductor & Integrated Circuits Nippon Bldg., 2-6-2, Ohte-machi, Chiyoda-ku, Tokyo 100-0004, Japan Tel: (03) 3270-2111 Fax: (03) 3270-5109

Fax: <49> (89) 9 29 30 00

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For further information write to:

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